DS05-11153-1E

MB8516S072CG-100/-100L

168-pin, 4 Clock, 2-bank, based on 8 M \times 8 Bit SDRAMs with SPD

DESCRIPTION

The Fujitsu MB8516S072CG is a fully decoded, CMOS Synchronous Dynamic Random Access Memory (SDRAM) Module consisting of eighteen MB81F64842C devices which organized as four banks of 8 M \times 8 bits and a 2K-bit serial EEPROM on a 168-pin glass-epoxy substrate.

The MB8516S072CG features a fully synchronous operation referenced to a positive edge clock whereby all operations are synchronized at a clock input which enables high performance and simple user interface coexistence.

The MB8516S072CG is optimized for those applications requiring high speed, high performance and large memory storage, and high density memory organizations.

This module is ideally suited for workstations, PCs, laser printers, and other applications where a simple interface is needed.

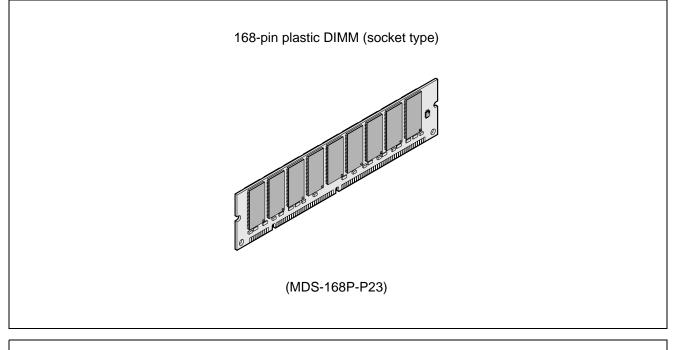
PRODUCT LINE & FEATURES

Parameter	MB8516S072CG					
Falameter	-100	-100L				
Clock Frequency	100 MF	Iz max.				
Burst Mode Cycle Time	10 ns min.					
Access Time from Clock	8.5 ns ma	x. (CL = 3)				
Operating Current	855 m.	A max.				
Power Down Mode Current (Icc2P)	36 mA max.	18 mA max.				
Self Refresh Current (Icc6)	18 mA max.	9 mA max.				

- Unbuffered 168-pin DIMM Socket Type (Lead pitch: 1.27 mm)
- Conformed to JEDEC Standard (4 CLK)
- Organization: 16,777,216 words × 72 bits
- Memory: MB81F64842C (8 M \times 8, 4-bank) \times 18 pcs.
- 3.3 V ±0.3 V Supply Voltage
- All input/output LVTTL compatible
- 4096 Refresh Cycle every 65.6 ms

- Auto and Self Refresh
- CKE Power Down Mode
- DQM Byte Masking (Read/Write)
- Serial Presence Detect (SPD) with Serial EEPROM: JEDEC Standard SPD Format
- Module size:
 - 1.0" (height) \times 5.25" (length) \times 0.157" (thickness)
- CL-trcd-trp: 3-3-3 clk min. @100 MHz,
 - 2-2-2 clk min. @66 MHz

■ PACKAGE



Package and Ordering Information

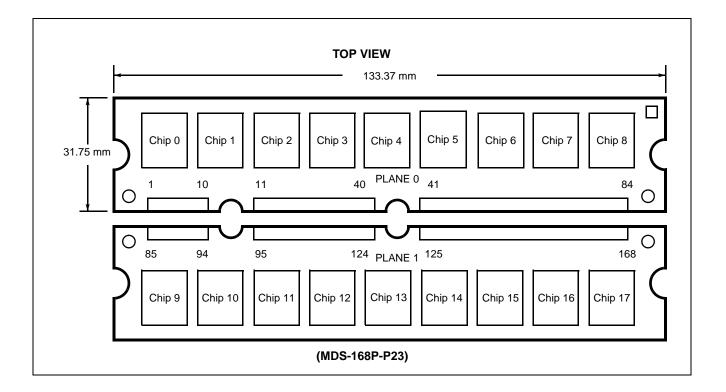
 - 168-pin DIMM, order as MB8516S072CG-100DG (DG = Gold Pad) MB8516S072CG-100LDG (LDG = Low power ver., Gold Pad)

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MB8516S072CG-100/-100L

■ PIN ASSIGNMENTS

Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name
1	Vss	29	DQMB ₁	57	DQ18	85	Vss	113	DQMB₅	141	DQ ₅₀
2	DQ ₀	30	CS ₀	58	DQ19	86	DQ32	114	CS ₁	142	DQ ₅₁
3	DQ ₁	31	N.C.	59	Vcc	87	DQ33	115	RAS	143	Vcc
4	DQ ₂	32	Vss	60	DQ20	88	DQ34	116	Vss	144	DQ ₅₂
5	DQ ₃	33	Ao	61	N.C.	89	DQ35	117	A 1	145	N.C.
6	Vcc	34	A ₂	62	N.C.	90	Vcc	118	Аз	146	N.C.
7	DQ4	35	A4	63	CKE1	91	DQ ₃₆	119	A5	147	N.C.
8	DQ₅	36	A ₆	64	Vss	92	DQ ₃₇	120	A7	148	Vss
9	DQ ₆	37	A8	65	DQ ₂₁	93	DQ38	121	A9	149	DQ53
10	DQ7	38	A10	66	DQ22	94	DQ39	122	BA ₀	150	DQ ₅₄
11	DQ8	39	BA ₁	67	DQ ₂₃	95	DQ40	123	A11	151	DQ55
12	Vss	40	Vcc	68	Vss	96	Vss	124	Vcc	152	Vss
13	DQ ₉	41	Vcc	69	DQ ₂₄	97	DQ ₄₁	125	CLK1	153	DQ56
14	DQ10	42	CLK ₀	70	DQ25	98	DQ ₄₂	126	N.C.	154	DQ57
15	DQ11	43	Vss	71	DQ ₂₆	99	DQ ₄₃	127	Vss	155	DQ ₅₈
16	DQ12	44	N.C.	72	DQ27	100	DQ44	128	CKE ₀	156	DQ59
17	DQ13	45	CS ₂	73	Vcc	101	DQ45	129	CS₃	157	Vcc
18	Vcc	46	DQMB ₂	74	DQ ₂₈	102	Vcc	130	DQMB ₆	158	DQ60
19	DQ ₁₄	47	DQMB ₃	75	DQ29	103	DQ ₄₆	131	DQMB7	159	DQ ₆₁
20	DQ15	48	N.C.	76	DQ30	104	DQ ₄₇	132	N.C.	160	DQ ₆₂
21	CB ₀	49	Vcc	77	DQ ₃₁	105	CB ₄	133	Vcc	161	DQ ₆₃
22	CB1	50	N.C.	78	Vss	106	CB₅	134	N.C.	162	Vss
23	Vss	51	N.C.	79	CLK ₂	107	Vss	135	N.C.	163	CLK ₃
24	N.C.	52	CB ₂	80	N.C.	108	N.C.	136	CB ₆	164	N.C.
25	N.C.	53	CB ₃	81	N.C.	109	N.C.	137	CB7	165	SA ₀
26	Vcc	54	Vss	82	SDA	110	Vcc	138	Vss	166	SA1
27	WE	55	DQ ₁₆	83	SCL	111	CAS	139	DQ48	167	SA ₂
28	DQMB ₀	56	DQ17	84	Vcc	112	DQMB ₄	140	DQ49	168	Vcc



■ PIN DESCRIPTIONS

Symbol	I/O	Function	Symbol	I/O	Function
Ao to A11, BA0, BA1	Ι	Address Input	DQ ₀ to DQ ₆₃	I/O	Data Input/Data Output
RAS	I	Row Address Strobe	CB ₀ to CB ₇	I/O	ECC Data Input/Output
CAS	I	Column Address Strobe	Vcc	_	Power Supply (+3.3 V)
WE	I	Write Enable	Vss	_	Ground (0 V)
DQMB ₀ to DQMB ₇	I	Data (DQ) Mask	N.C.	_	No Connection
CLK₀ to CLK ₃	I	Clock Input	SA ₀ to SA ₂	I	Serial PD Address Input
CKE0, CKE1	I	Clock Enable	SCL	I	Serial PD Clock
\overline{CS}_0 to \overline{CS}_3	I	Chip Select	SDA	I/O	Serial PD Address/Data Input/Output

■ SERIAL-PD INFORMATION

Byte	Function Described		Hex Value
Буге	Function Described		-100/100L
0	Defines Number of Bytes Written into	128 Byte	80h
	Serial Memory at Module Manufacture		
1	Total Number of Bytes of SPD Memory Device	256 Byte	08h
2	Fundamental Memory Type	SDRAM	04h
3	Number of Row Addresses	12	0Ch
4	Number of Column Addresses	9	09h
5	Number of Module Banks	2 bank	02h
6	Data Width	72 bit	48h
7	Data Width (Continuation)	+0	00h
8	Interface Type	LVTTL	01h
9	SDRAM Cycle Time (Highest CAS Latency)	10 ns	A0h
10	SDRAM Access from Clock (Highest CAS Latency)	8.5 ns	85h
11	DIMM Configuration Type	ECC	02h
12	Refresh Rate/Type	Self, Normal	80h
13	Primary SDRAM Width	×8	08h
14	Error Checking SDRAM Width	×8	08h
15	Minimum Clock Delay for Back to Back Random Column	1 Cycle	01h
	Addresses		
16	Burst Lengths Supported	1, 2, 4, 8, Page	8Fh
17	Number of Banks on Each SDRAM Device	4 bank	04h
18	CAS Latency	2, 3	06h
19	CS Latency	0	01h
20	Write Latency	0	01h
21	SDRAM Module Attributes	UN-buffer	00h
22	SDRAM Device Attributes	*1	0Eh
23	SDRAM Cycle Time (2nd. Highest CAS Latency)	15 ns	F0h
24	SDRAM Access from Clock (2nd. Highest CAS Latency)	9 ns	90h
25	SDRAM Cycle Time (3rd. Highest CAS Latency)	No Support	00h
26	SDRAM Access from Clock (3rd. Highest CAS Latency)	No Support	00h
27	Minimum Row Precharge Time (trp)	30 ns	1Eh
28	Row Activate to Row Activate Min. (trrd)	20 ns	14h
29	RAS to CAS Delay Min. (trcd)	30 ns	1Eh
30	Minimum RAS Pulse Width	60 ns	3Ch
31	Module Bank Density	64 MByte	10h
32 to 61	Unused Storage Locations		00h
62	SPD Data Revision Code	1	01h
63	Checksum for Byte 0 to 62	*2	6Ah
64 to 98	Manufacturer's Information: Unused Storage	_	00h
99 to 125	Vendor Specific Data: Unused Storage	_	00h
126	Intel specification Frequency	66MHz	66h
127	Intel specification Details for 66MHz Support	CL=2, 3	FFh
128+	Unused Storage Locations		_

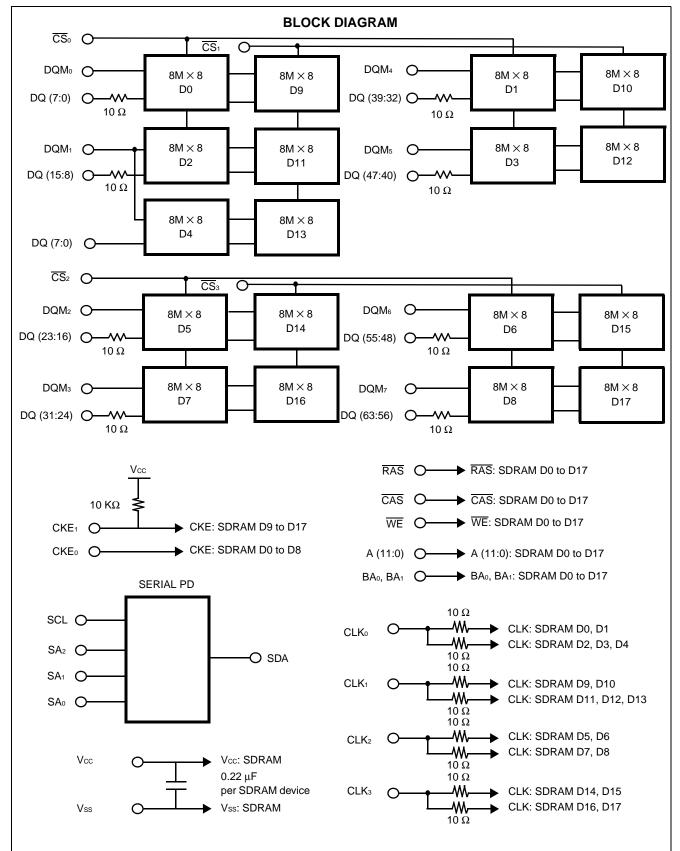
Note: Any write operation must NOT be executed into the addresses of Byte 0 to Byte 127. Some or all data stored into Byte 0 to Byte 127 may be broken.

*1. Byte 22: SDRAM Device Attributes

Bit7	Bit6	Bit5	Bit4	Bit3	Bit2	Bit1	Bit0
TBD	TBD	Upper Vcc tolerance	Lower Vcc tolerance	Supports Write 1 /Read Burst	Supports Precharge All	Supports Auto- precharge	Supports Early RAS Precharge
0	0	0	0	1	1	1	0

*2. Byte 63: Checksum for Bytes 0 to 62 This byte is the checksum for bytes 0 through 62. This byte contains the value of the low 8-bits of the arithmetic sum of bytes 0 through 62.

BLOCK DIAGRAM



■ ABSOLUTE MAXIMUM RATINGS (See WARNING)

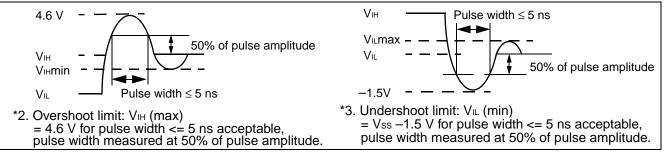
Parameter	Symbol	Va	Unit	
Farameter	Symbol	Min.	Max.	Unit
Supply Voltage*	Vcc	-0.5	+4.6	V
Input Voltage*	Vin	-0.5	+4.6	V
Output Voltage*	Vout	-0.5	+4.6	V
Storage Temperature	Тѕтс	-55	+125	°C
Power Dissipation	PD	—	18.0	W
Output Current (D.C.)	Іоит	-50	+50	mA

* : Voltages referenced to Vss (= 0 V)

RECOMMENDED OPERATING CONDITIONS

Parameter	Notes	Symbol		Unit		
Falameter	NOLES		Min.	Тур.	Max.	Onit
Supply Voltage	*1	Vcc	3.0	3.3	3.6	V
Supply voltage	I	Vss	0	0	0	V
Input High Voltage, All Inputs	*1, 2	Vін	2.0	—	Vcc +0.5	V
Input Low Voltage, All Inputs	*1, 3	VIL	-0.5	_	0.8	V
Ambient Temperature		TA	0		+70	°C

*1. Voltages referenced to Vss (= 0 V)



WARNING: The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.

Always use semiconductor devices within their recommended operating conditionranges. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their FUJITSU representatives beforehand.

WARNING: Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

■ CAPACITANCE

			(Vcc = +3	.3 V, f = 1 MHz, T	a = +25°C)
Parame	tor	Symbol	Va	lue	Unit
Falalie		Symbol	Min.	Max.	Onit
	Ao to A11, BAo, BA1	CIN1	_	106	pF
	RAS, CAS, WE	CIN2	—	94	pF
	\overline{CS}_0 to \overline{CS}_3	Сімз	—	30	pF
	CKE ₀ , CKE ₁	CIN4		50	pF
Input Capacitance	CLK ₀ to CLK ₃	Сіль		45	pF
	DQMB ₀ to DQMB ₇	CING		28	pF
	SCL	CSCL		6	pF
	SA0, SA1, SA2	CSA		8	pF
	SDA	CSDA		7	pF
Input/Output Capacitance	DQ ₀ to DQ ₆₃	CDQ	—	21	pF
	CB ₀ to CB ₇	Ссв		20	pF

■ DC CHARACTERISTICS

(At recommended operating conditions unless otherwise noted.) Notes 1, 2

					Value		
Parameter	Notes	Symbol	Condition	Min	M	ax.	Unit
				Min.	Std. ver.	Low ver.	
Operating Current (Average Power Supply Current)	*3	Icc1s	Burst: Length = 1 t_{RC} = min for BL = 1 t_{CK} = min One Bank Active, Outputs Open Addresses changed up to 1-time during t_{CK} (min.) $0 V \le V_{IN} \le V_{IL}$ (max.) V_{IH} (min.) $\le V_{IN} \le V_{CC}$		8	55	mA
		Ісс2р	$\begin{array}{l} CKE = V_{\text{IL}}, All \; Banks \; Idle \\ tck = min, \; Power \; Down \; Mode \\ 0 \; V \leq V_{\text{IN}} \leq V_{\text{IL}} \; (max.) \\ V_{\text{IH}} \; (min.) \leq V_{\text{IN}} \leq V_{\text{CC}} \end{array}$	_	36	18	mA
Precharge Standby Current (Power Supply Current)		Icc2ps	$\begin{array}{l} CKE = V_{\text{IL}}, All \; Banks \; Idle \\ CLK = H \; or \; L, \; Power \; Down \; Mode \\ 0 \; V \leq V_{\text{IN}} \leq V_{\text{IL}} \; (max.) \\ V_{\text{IH}} \; (min.) \leq V_{\text{IN}} \leq V_{\text{CC}} \end{array}$	_	18	9	mA
	ower *3 rrent)	Icc2N	CKE = V _{IH} , All Banks Idle, t _{CK} = min NOP commands only, Input signals (except to CMD) are changed 1-time during 3 clock cycles $0 V \le V_{IN} \le V_{IL}$ (max.) V_{IH} (min.) $\le V_{IN} \le V_{CC}$		180		mA
		Ісс2№	$\begin{array}{l} CKE=V_{IH},All\;Banks\;Idle\\ CLK=H\;or\;L,Input\;signal\;are\;stable\\ 0\;V\leqV_{IN}\leqV_{IL}\;(max.)\\ V_{IH}\;(min.)\leqV_{IN}\leqV_{CC} \end{array}$	_		mA	
		Іссзр	$\begin{array}{l} CKE = V_{\text{IL}}, Any \ Bank \ Active \\ tck = min. \\ 0 \ V \leq V_{\text{IN}} \leq V_{\text{IL}} \left(max.\right) \\ V_{\text{IH}} \left(min.\right) \leq V_{\text{IN}} \leq V_{\text{Cc}} \end{array}$	_	36	18	mA
Activo Standby		Іссзря	$\begin{array}{l} CKE = V_{IL}, Any \ Bank \ Active \\ CLK = H \ or \ L \\ 0 \ V \leq V_{IN} \leq V_{IL} \ (max.) \\ V_{IH} \ (min.) \leq V_{IN} \leq V_{CC} \end{array}$		18	9	mA
Active Standby Current (Power Supply Current)	*3	Іссзи	$\begin{array}{l} CKE = V_{IH}, Any Bank Active \\ tck = min., NOP commands only, Input \\ signals (except to CMD) are changed \\ 1\text{-time} during 3 clock cycles \\ 0 V \leq V_{IN} \leq V_{IL} (max.) \\ V_{IH} (min.) \leq V_{IN} \leq V_{CC} \end{array}$		2	70	mA
		Іссзия	$\begin{array}{l} CKE = V_{IH}, Any Bank Active \\ CLK = H or L \\ 0 V \leq V_{IN} \leq V_{IL} (max.) \\ V_{IH} (min.) \leq V_{IN} \leq V_{CC} \end{array}$	_	з	36	mA

(Continued)

(Continued)

		es Symbol Condition						
Parameter N	Notes			Min.	Ma	Unit		
				wiin.	Std. ver.	Low ver.		
Burst Mode Current (Average Power Supply Current)	*3	Icc4	$\begin{array}{l} t_{CK} = min, \ Burst \ Length = 4 \\ Outputs \ Open, \ All \ Banks \ Active \\ Gapless \ Data \\ 0 \ V \leq V_{IN} \leq V_{IL} \ (max.) \\ V_{IH} \ (min.) \leq V_{IN} \leq V_{CC} \end{array}$		10	80	mA	
Auto-refresh Current (Average Power Supply Current)	*3	Icc5	Auto Refresh tck = min tRc = min $0 V \le V_{IN} \le V_{IL}$ (max.) V_{IH} (min.) $\le V_{IN} \le V_{CC}$		3060		mA	
Self-refresh Current (Average Power Supply Current)	*3	Icc6	$\begin{array}{l} \text{Self-Refresh} \\ t_{CK} = \min. \\ \text{CKE} \leq 0.2 \text{ V} \\ 0 \text{ V} \leq V_{\text{IN}} \leq V_{\text{IL}} (\text{max.}) \\ \text{V}_{\text{IH}} (\text{min.}) \leq V_{\text{IN}} \leq V_{\text{CC}} \end{array}$	_	18	9	mA	
Input Leakage Current (All Inputs)		II (L)	$0 V \le V_{IN} \le V_{CC}$ All other pins not under test = 0 V	-30	3	60	μΑ	
Output Leakage Currer	nt	lo (L)	$0 V \le V_{IN} \le V_{CC}$ Output is disabled (Hi-Z)	-10	1	0	μΑ	
LVTTL Output High Voltage	*4	Vон	Іон = –2.0 mA	2.4	_	_	V	
LVTTL Output Low Voltage	*4	Vol	lo∟ = +2.0 mA	_	0	.4	V	

Notes: *1. An initial pause (DESL on NOP) of 200 μs is required after power-on followed by a minimum of eight Auto-refresh cycles.

*2. DC characteristics is the Serial PD standby state (VIN = Vss or Vcc).

*3. Icc depends on the output termination, load conditions, clock cycle rate and signal clock rate. The specified values are obtained with the output open and no termination register.

*4. Voltages referenced to $V_{SS} = V_{SSQ} (= 0 V)$.

■ AC CHARACTERISTICS

(1) BASE CHARACTERISTICS

(At recommended operating conditions unless otherwise noted.) Notes 1, 2, 3

No.	Parameter Notes	Notes		MB8516 -100	Unit	
				Min.	Max.	
1	Clock Period	CL = 3	t скз	10	—	ns
	Clock Fellou	CL = 2	tск2	15	—	ns
2	Clock High Time		tсн	3.5	—	ns
3	Clock Low Time		tc∟	3.5	—	ns
4	Input Setup Time	tsı	3	_	ns	
5	Input Hold Time	tнı	1	—	ns	
6	Output Valid from Clock *4, *	CL = 3	tасз	—	8.5	
0	$(t_{CLK} = min)$ 4,	CL = 2	t _{AC2}	—	9	ns
7	Output in Low-Z	6	t∟z	0	—	ns
8	Output in High-Z	6 CL = 3	t HZ3	3	8.5	ns
0		CL = 2	tHZ2	3	9	ns
9	Output Hold Time	6	tон	3	—	ns
10	Time between Refresh		tref	—	65.6	ms
11	Transition Time		t⊤	0.5	2	ns
12	CKE Setup Time for Power Down Exit Tim	e	t cksp	3		ns

(2) BASE VALUES FOR CLOCK COUNT/LATENCY

No.	Parameter Notes		Symbol	MB8516 -100/	Unit	
				Min.	Max.	
1	RAS Cycle Time *7		t RC	90	—	ns
2	RAS Precharge Time	t RP	30	_	ns	
3	RAS Active Time	tras	60	110000	ns	
4	RAS to CAS Delay Time *8	trcd	30	_	ns	
5	Write Recovery Time		twr	10	_	ns
6	RAS to RAS Bank Active Delay Time		t RRD	20		ns
7	Data-in to Precharge Lead Time		t dpl	10	_	ns
8	Data-in to Active/Refresh Command Period	CL = 3	tdal3	2 cyc + t _{RP}	_	ns
0	Data-in to Active/Reliesh Command Penod	CL = 2	tdal2	1 cyc + t _{RP}	—	ns
9	Mode Register Set Cycle Time		trsc	20		ns

(3) CLOCK COUNT FORMULA (*9)

 $Clock \ge \frac{Base Value}{Clock Period}$ (Round off a whole number)

(4) LATENCY (The latency values on these parameters are fixed regardless of clock period.)

No.	Parameter	Symbol	MB8516S072CG -100/100L	Unit	
1	CKE to Clock Disable			1	Cycle
2	DQM to Output in High-Z		Idqz	2	Cycle
3	DQM to Input Data Delay		Idqd	0	Cycle
4	Last Output to Write Command Delay		lowd	2	Cycle
5	Write Command to Input Data Delay		lowd	0	Cycle
6	Procharge to Output in High 7 Delay	CL = 3	Ігонз	3	Cycle
	Precharge to Output in High-Z Delay	CL = 2	IROH2	2	Cycle
7	Durat Step Command to Output in Lligh 7 Delay	CL = 3	Івѕнз	3	Cycle
	Burst Stop Command to Output in High-Z Delay	CL = 2	Івѕн2	2	Cycle
8	CAS to CAS Delay (min)	Ісср	1	Cycle	
9	CAS Bank Delay (min)		Ісвр	1	Cycle

Notes: *1. An initial pause (DESL on NOP) of 200 μs is required after power-up followed by a minimum of eight Auto-refresh cycles.

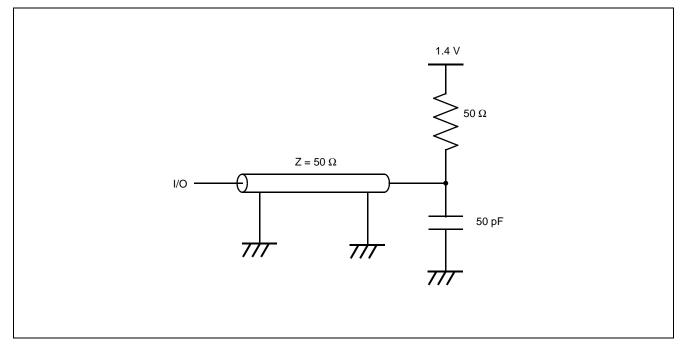
- *2. 1.4 V or V_{REF} is the reference level for measuring timing of signals. Transition times are measured between V_{IH} (min) and V_{IL} (max).
- *3. AC characteristics assume $t_T = 1$ ns and 50 pF of capacitive load.
- *4. Maximum value of CL = 2 depends on tck.
- *5. tac also specifies the access time at burst mode except for first access.
- *6. Specified where output buffer is no longer driven. toн, tLz, and tHz define the times at which the output level achieves ±200 mV.
- *7. Actual clock count of trc (Irc) will be sum of clock count of tras (Iras) and trp (Irp).
- *8. Operation within the tRCD (min) ensures that access time is determined by tRCD (min) + tAC (max); if tRCD is greater than the specified tRCD (min), access time is determined by tAC.
- *9. All base values are measured from the clock edge at the command input to the clock edge for the next command input.

All clock counts are calculated by a simple formula:

clock count equals base value divided by clock period (round off to a whole number).

*Source: See MB81F64842C Data Sheet for details on the electrical.





■ SERIAL PRESENCE DETECT(SPD) FUNCTION

1. PIN DESCRIPTIONS

SCL (Serial Clock)

SCL input is used to clock all data input/output of SPD

SDA (Serial Data)

SDA is a common pin used for all data input/output of SPD. The SDA pull-up resistor is required due to the open-drain output.

SA₀, SA₁, SA₂ (Address)

Address inputs are used to set the least significant three bits of the eight bits slave address. The address inputs must be fixed to select a particular module and the fixed address of each module must be different each other.

2. SPD OPERATIONS

CLOCK and DATA CONVENTION

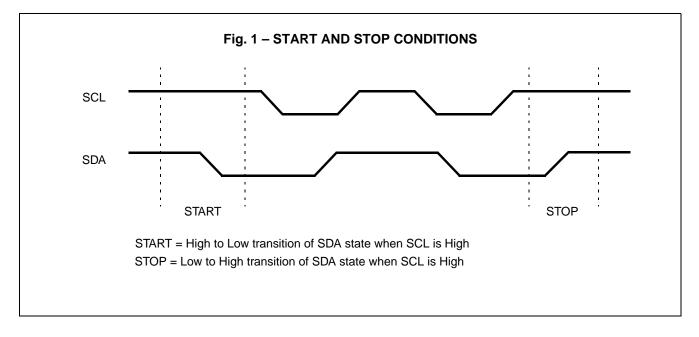
Data states on the SDA can change only during SCL = Low. SDA state changes during SCL = High are indicated start and stop conditions. Refer to Fig. 1 below.

START CONDITION

All commands are preceded by a start condition, which is a transition of SDA state from High to Low when SCL = High. SPD will not respond to any command until this condition has been met.

STOP CONDITION

All read or write operation must be terminated by a stop condition, which is a transition of SDA state from Low to High when SCL = High. The stop condition is also used to make the SPD into the state of standby power mode after a read sequence.



ACKNOWLEDGE

Acknowledge is a software convention used to indicate successful data transfer. The transmitting device, either master or slave, will release the bus after transmitting eight bits. During the ninth clock cycle the receiver will put the SDA line to Low in order to acknowledge that it received the eight bits of data.

The SPD will respond with an acknowledge when it received the start condition followed by slave address issued by master.

In the read operation, the SPD will transmit eight bits of data, release the SDA line and monitor the line for an acknowledge. If an acknowledge is detected and no stop condition is issued by master, the SPD will continue to transmit data. If an acknowledge is not detected, the SPD will terminated further data transmissions. The master must then issue a stop condition to return the SPD to the standby power mode.

In the write operation, upon receipt of eight bits of data the SPD will respond with an acknowledge, and await the next eight bits of data, again responding with an acknowledge until the stop condition is issued by master.

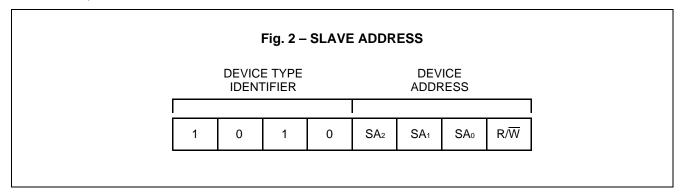
SLAVE ADDRESS ADDRESSING

Following a start condition, the master must output the eight bits slave address. The most significant four bits of the slave address are device type identifier. For the SPD this is fixed as 1010[B]. Refer to the Fig. 2 below.

The next three significant bits are used to select a particular device. A system could have up to eight SPD devices —namely up to eight modules— on the bus. The eight addresses for eight SPD devices are defined by the state of the SA₀, SA₁ and SA₂ inputs.

The last bit of the slave address defines the operation to be performed. When R/\overline{W} bit is "1", a read operation is selected, when R/\overline{W} bit is "0", a write operation is selected.

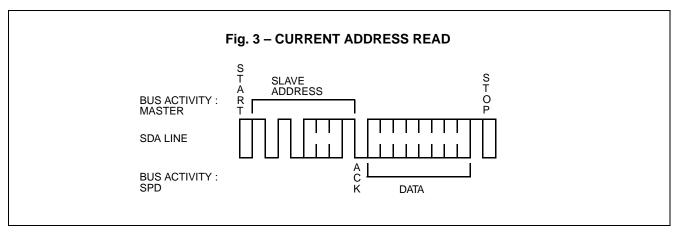
Following the start condition, the SPD monitors the SDA line comparing the slave address being transmitted with its slave address (device type and state of SA₀, SA₁, and SA₂ inputs). Upon a correct compare the SPD outputs an acknowledge on the SDA line. Depending on the state of the R/W bit, the SPD will execute a read or write operation.



3. READ OPERATIONS

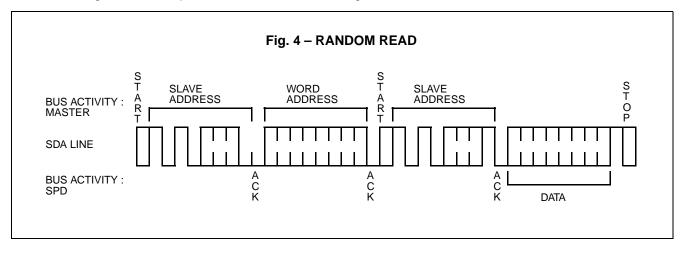
CURRENT ADDRESS READ

Internally the SPD contains an address counter that maintains the address of the last data accessed, incremented by one. Therefore, if the last access (either a read or write operation) was to address(n), the next read operation would access data from address(n+1). Upon receipt of the slave address with the R/W bit = "1", the SPD issues an acknowledge and transmits the eight bits of data during the next eight clock cycles. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 3 for the sequence of address, acknowledge and data transfer.



RANDOM READ

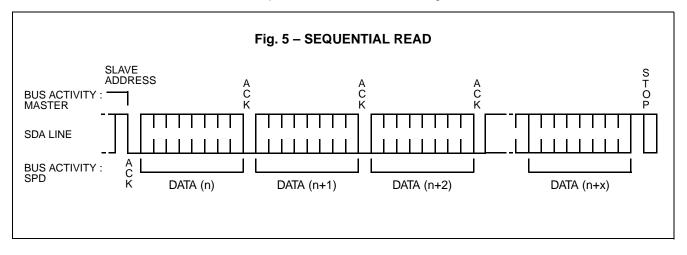
Random Read operations allow the master to access any memory location in a random manner. Prior to issuing the slave address with the R/W bit = "1", the master must first perform a "dummy" write operation on the SPD. The master issues the start condition, and the slave address followed by the word address. After the word address acknowledge, the master immediately reissues the start condition and the slave address with the R/W bit = "1". This will be followed by an acknowledge from the SPD and then by the eight bits of data. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 4 for the sequence of address, acknowledge and data transfer.



SEQUENTIAL READ

Sequential Read can be initiated as either a current address read or random read. The first data are transmitted as with the other read mode, however, the master now responds with an acknowledge, indicating it requires additional data. The SPD continues to output data for each acknowledge received. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 5 for the sequence of address, acknowledge and data transfer.

The data output is sequential, with the data from address(n) followed by the data from address(n+1). The address counter for read operations increments all address bits, allowing the entire memory contents to be serially read during one operation. At the end of the address space (address 255), the counter "rolls over" to address 0 and the SPD continues to output data for each acknowledge received.



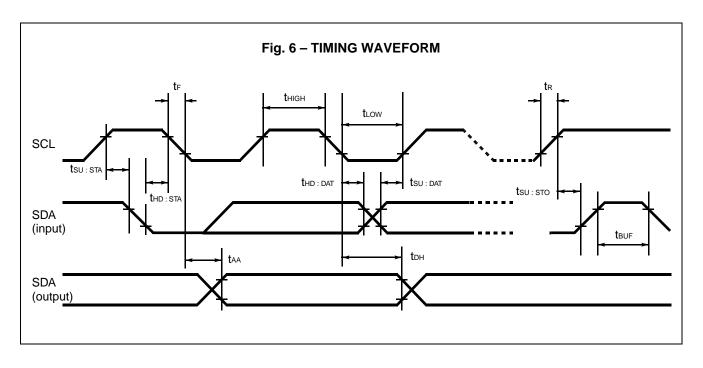
4. DC CHARACTERISTICS

Parameter	Note	Symbol	Condition	Value		Unit
Farameter	Note		Condition	Min.	Max.	Unit
Input Leakage Current		Sili	$0~V \leq V_{\text{IN}} \leq V_{\text{CC}}$	-10	10	μA
Output Leakage Current		SILO	$0 \text{ V} \leq \text{V}_{\text{OUT}} \leq \text{V}_{\text{CC}}$	-10	10	μA
Output Low Voltage	*1	Svol	lo∟ = 3.0 mA	—	0.4	V

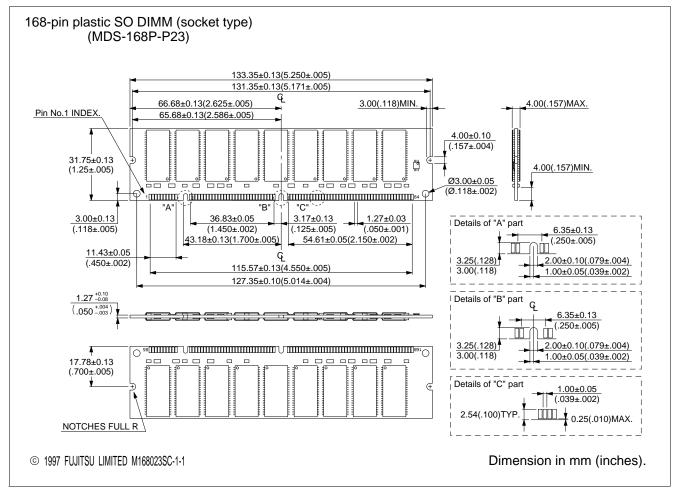
Note: *1. Referenced to Vss.

5. AC CHARACTERISTICS

No.	Parameter	Symbol	Value		Unit
		Symbol	Min.	Max.	Onit
1	SCL Clock Frequency	fsc∟	—	100	KHz
2	Noise Suppression Time Constant at SCL, SDA Inputs	Tı		100	ns
3	SCL Low to SDA Data Out Valid	taa	_	3.5	μs
4	Time the Bus Must Be Free Before a New Transmission Can Start	tBUF	4.7	—	μs
5	Start Condition Hold Time	thd:sta	4.0	_	μs
6	Clock Low Period	tLow	4.7	—	μs
7	Clock High Period	tнigн	4.0	—	μs
8	Start Condition Setup Time	tsu:sta	4.7	—	μs
9	Data in Hold Time	thd:dat	0	—	μs
10	Data in Setup Time	tsu:dat	250	_	ns
11	SDA and SCL Rise Time	tR		1	μs
12	SDA and SCL Fall Time	t⊧	—	300	ns
13	Stop Condition Setup Time	tsu:sto	4.7	—	μs
14	Data Out Hold Time	tон	100	—	ns
15	Write Cycle Time	twr	—	15	ms



PACKAGE DIMENSION



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